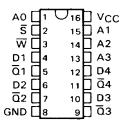
#### STATIC RANDOM-ACCESS MEMORIES

- Fully Decoded RAMs Organized as 16 Words of Four Bits Each
- Schottky-Clamped for High Speed: Read Cycle Time . . . 25 ns Typical Write Cycle Time . . . 25 ns Typical
- Choice of Three-State or Open-Collector Outputs
- Compatible with Most TTL and I<sup>2</sup>L Circuits
- Chip-Select Input Simplifies External Decoding

SN54S189B, SN54S289B . . . J OR W PACKAGE SN74S189B, SN74S289B . . . J OR N PACKAGE (TOP VIEW)



#### description

These 64-bit active-element memories are monolithic Schottky-clamped transistor-transistor logic (TTL) arrays organized as 16 words of four bits each. They are fully decoded and feature a chip-select input to simplify decoding required to achieve expanded system organization. The memories feature p-n-p input transistors that reduce the low-level input current requirement to a maximum of -0.25 milliamperes, only one-eighth that of a Series 54S/74S standard load factor. The chip-select circuitry is implemented with minimal delay times to compensate for added system decoding.

#### write cycle

The information applied at the data input is written into the selected location when the chip-select input and the write-enable input are low. While the write-enable input is low, the 'S189B output is in the high-impedance state and the 'S289B output is off. When a number of outputs are bus-connected, this high-impedance or off state will neither load nor drive the bus line, but it will allow the bus line to be driven by another active output or a passive pull-up.

### read cycle

The stored information (complement of information applied at the data input during the write cycle) is available at the output when the write-enable input is high and the chip-select input is low. When the chip-select input is high, the 'S189B output will be in the high-impedance state and the 'S289B output will be off.

#### **FUNCTION TABLE**

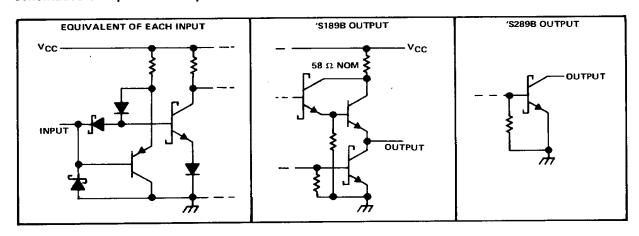
	INP	UTS	′S189B	'S289B		
FUNCTION	CHIP SELECT	WRITE ENABLE	OUTPUT	OUTPUT		
Write	L	L	High Impedance	Off		
Read	L	Н	Complement of Data Entered	Complement of Data Entered		
Inhibit	Н	X	High Impedance	Off		

 $H \equiv high level, L \equiv low level, X \equiv irrelevant$ 



#### logic symbols functional block diagram 'S189B A0 (1) **RAM 16 X 4** A0 (15) A1 (15) A1 64-BIT MEMORY 1-OF-16 DECODERS ADDRESS (14)MATRIX A2 ORGANIZED 16-X-4 A2 (14) (13) А3-(2) <u>s</u> – G1 A3 (13) (3) R/W. 1 EN [READ] 1 C2 [WRITE] (5) Q1 (4) $A \nabla$ D1-A. 2D (7) Q2 (6) CHIP SELECT (S) D2-(9) <u>O</u>3 WRITE AND SENSE (10) AMPLIFIER CONTROL D3-(11) Q4 READ/WRITE (R/W) (12) D4 -D1 (4) D2-(10) 'S289B RAM 16 X 4 D4 (12) (1) AO-(15) (9) A1-A2 (14) A 📆 Ō1 **0**2 $\overline{\mathbf{Q}}$ 3 $\overline{\mathbf{Q}}$ 4 (13) A3 (2) $\bar{s}$ G1 (3) R/W -1 EN [READ] 1 C2 [WRITE] (5) (4) **A** ♀ - <u>ā</u>1 A, 2D D1 -(7) (6) - <u>Q</u>2 D2 (10) (9) Q3 D3 (11) (12) Q4 D4

### schematics of inputs and outputs



# 

NOTE 1: Voltage values are with respect to network ground terminal.

#### recommended operating conditions

			SN54S'			SN74S'			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	OWII
Supply voltag	je, V <sub>CC</sub>		4.5	5	5.5	4.75	5	5.25	٧
High-level output voltage, VOH 'S289B					5.5			5.5	٧
High-level out	tput current, IOH	'S189B			- 2			-6.5	mA
Low-level out	tput current, IOL				16			16	mA
Width of writ	Vidth of write pulse (write enable low), tw(wr)					25			ns
·	Address before write pulse, t <sub>su(da)</sub>		O↓			0+			1
Setup time	Data before end of write pulse, te	25↑			25↑			ns	
	Chip-select before end of write pu	25↑	•		25↑				
	Address after write pulse, th(ad)		31			01			
Hold time	Data after write pulse, th(da)	01			01			ns	
	Chip-select after write pulse, th(S	01			01			1	
Operating fre	Operating free-air temperature, TA				125	0		70	°C

<sup>†</sup> The arrow indicates the transition of the write-enable input used for reference: † for the low-to-high transition, † for the high-to-low transition.



# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS†				'S189B		'S289B			1
	PARAMETER				MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage				2			2			V
VIL	Low-level input voltage						0.8			0.8	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
Vικ	input clamp voltage	V <sub>CC</sub> = MIN,	$I_{\parallel} = -18 \text{ m/s}$	A			- 1.2			-1.2	V
	High level output valtage	V <sub>CC</sub> = MIN,	$V_{IH} = 2 V$	SN54S'	2.4	3.4					V
∨он	High-level output voltage	$V_{1L} = 0.8 V$	IOH = MAX	SN74S'	2.4	3.2					
	High-level output current	V <sub>CC</sub> = MIN,	$V_{IH} = 2 V$	$V_0 = 2.4 \text{ V}$						40	μА
ІОН		V <sub>IL</sub> = 0.8 V		V <sub>O</sub> = 5.5 V						100	] #^
``.	Low-level output voltage	V <sub>CC</sub> = MIN,	$V_{IH} = 2 V$			0.35	0.5		0.35	0.5	V
VOL		$V_{IL} = 0.8 V$ ,	IOL = 16 m	A	0.35 0.5			0.55			L
	Off-state output current,	V <sub>CC</sub> = MAX,	$V_{IH} = 2 V$		1		50				μА
lozh	high-level voltage applied	V <sub>IL</sub> = 0.8 V,	$V_{OH} = 2.4$	V			50				
	Off-state output current,	V <sub>CC</sub> = MAX,	$V_{IH} = 2 V$				- 50				μА
lozL	low-level voltage applied	$V_{IL} = 0.8 V,$	V <sub>OL</sub> = 0.4 \	V							μ, τ
	Input current at maximum	VCC = MAX,	V: = 5.5.V				1			1	mA
11	input voltage	VCC - MAA,	V  - 3.5 V								
ΊΗ	High-level input current	V <sub>CC</sub> = MAX,	$V_1 = 2.7 \text{ V}$		İ		25			25	μА
I <sub>I</sub> L	Low-level input current	V <sub>CC</sub> = MAX,	$V_1 = 0.5 V$	-			- 250			- 250	μА
1	Short-circuit output	VCC = MAX			- 30		- 100				mA
los	current <sup>§</sup>	VCC - WAX						L			,
Icc	Supply current	V <sub>CC</sub> = MAX,	See Note 2	-		75	110	İ	75	105	mA

NOTE 2: ICC is measured with the read/write and chip-select inputs grounded. All other inputs at 4.5 V, and the outputs open.

# 'S189B switching characteristics over recommended operating ranges of TA and VCC (unless otherwise noted)

				SI	N54S18	9B	SN74S189B			UNIT
	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT	
ta(ad)	Access time from address	cess time from address			25	50		25	35	ns
ta(S)	Access time from chip select		$C_L = 30 pF$ , See Note 3		18	25		18	22	ns
	(enable_time)			<u> </u>						1
t <sub>SR</sub>	Sense recovery time	nse recovery time			22	40		22	35	ns
<sup>t</sup> PXZ	Disable time from high	From S	C <sub>L</sub> = 5 pF,		12	25		12	17	ns
	ar low level From W		See Note 3		12	30		12	25	] '''

# 'S289B switching characteristics over recommended operating ranges of TA and VCC (unless otherwise noted)

			SN54S289B			SN74S289B			T	
	PARAMETER	TEST CONDITIONS	MIN	IN TYP‡	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT	
t <sub>a(ad)</sub>	Access time from address	1			25	50	1	25	35	ns
t <sub>a</sub> (S)	Access time from chip-sele (enable time)	ct	$C_L = 30 \text{ pF},$ $R_{L1} = 300 \Omega,$ $R_{L2} = 600 \Omega,$ See Note 3		18	25		18	22	ns
tSR	Sense recovery time				12			12	35	ns
	Propagation delay time,	From S							17	
<sup>t</sup> PLH	output (disable time)			12	30		12	25	ns	

<sup>†</sup>For conditions shown as MIN or MAX use the appropriate value specified under recommended operating conditions.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $<sup>^{\</sup>ddagger}$ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25 °.

<sup>&</sup>lt;sup>§</sup>Duration of the short circuit should not exceed one second.